Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,862	ANVIN ET AL.	
Examiner	Art Unit	
BENJAMIN P. GEIB	2181	

	SEAR	CHED			
Class	Subclass	Date	Examiner		
712	244	7/3/2008	BPG		
712	235	7/3/2008	BPG		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
712	244	7/3/2008	BPG		
PGPub te	PGPub text search		BPG		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Updated EAST search	7/3/2008	BPG
Updated NPL search (Google Scholar, Citeseer, IEEE Xplore)	7/3/2008	BPG
Inventor name search	7/3/2008	BPG